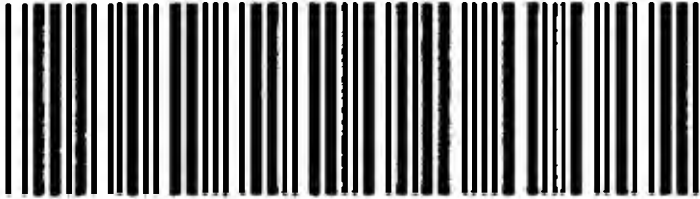


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/709,362	HATHAWAY ET AL.	
	Examiner	Art Unit	
	Toan M. Le	2863	

SEARCHED			
Class	Subclass	Date	Examiner
702	125	7/6/2005	TL
702	182	7/6/2005	TL
716	6	7/6/2005	TL
702	79	7/6/2005	TL
702	89	7/6/2005	TL
702	176	7/6/2005	TL
Above	Updated	12/20/2005	TL

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Static Timing Analysis; Path; Location	7/7/2005	TL
Static Timing Analysis; Spatial; Correlation; Path; Region	7/6/2005	TL
702/182,125,79,89,176 (Timing Analysis)	12/20/2005	TL
716/6 (Timing Analysis)	12/20/2005	TL
East- See Search History Printout	12/20/2005	TL
IEEE Xplore, Web	12/20/2005	TL